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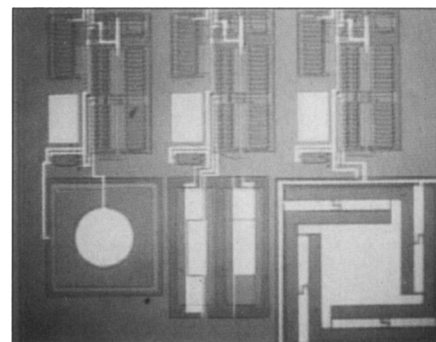
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ON THE COVER: Ferroelectric thin films are being applied in a diverse range of applications, including microelectromechanical systems. Some examples are (from left to right) an acoustic sensor, a double supported microbeam accelerometer, and a tactile force sensor. For more information, see the section that begins on page 29.

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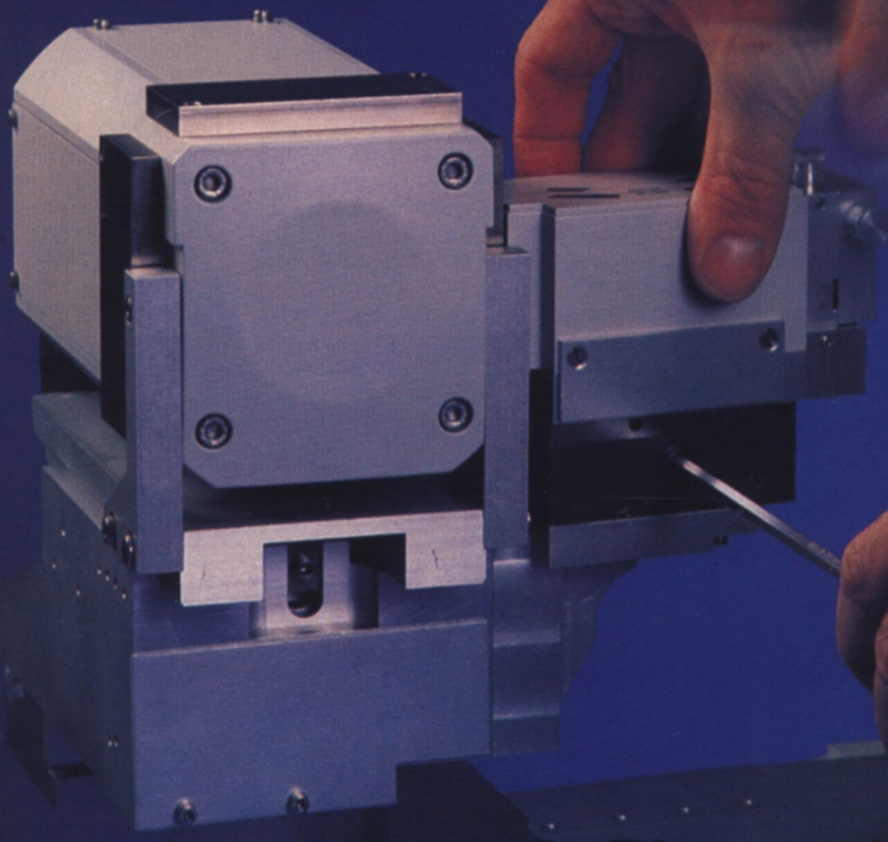
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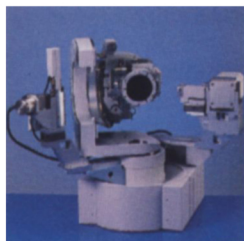
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